



Cutting the cost of analog test

Reduce Cost of ADC Test with LinBIST

Testing ADCs can be costly and slow - LinBIST overcomes this with on-chip test

- Can **save 90%** of test cost
- Test analog circuits on digital testers giving a **simple pass/fail** signal
- **Pushbutton generation** of Built-In Self-Test logic
- No external data transfer, so **no testing bottlenecks**

Easy to Implement



The LinBIST EDA tool generates a Built-In Self-Test (BIST) block able to fully test your convertor. This easily integrates into your design with a clock and connections to the ADC. At test time the BIST block responds with a pass/fail signal. More complex tests (and device characterization) can be supported via standard interfaces.

Additional Benefits

- **Concurrent testing** of many ADCs
- Less noisy environment gives **faster test**
- Suitable for wafer sort *and* final test
- **Patented algorithms** minimize BIST area

ATEEDA

- Experts in analog test
- **Proven capability** in production
- LinBIST will also cover DACs, PLLs, Vref and SerDes

Find Out More

To find out more, please contact the ATEEDA sales department by e-mail at sales@ateeda.com or by calling +44 131 272 2754 to arrange a conference call or meeting. Alternatively please visit our website at www.ateeda.com.